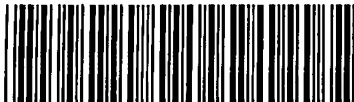


Search Notes

Application/Control No.

10/542,065

Examiner

Sow-Fun Hon

Applicant(s)/Patent under
Reexamination

FUKUOKA ET AL.

Art Unit

1772

SEARCHED

Class	Subclass	Date	Examiner
428	1.1,1.3	7/18/2007	SH
252	585		
	299.01		
349	96,98		
	113,115		
	176,194		
	118		
430	20		
522	1-2		
264	494,496		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
428	1.1,1.3	7/18/2007	SH
430	20		
522	1-2		
252/585,299/01; 264/494,496			

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST(USPGPUB;USPAT;USOCR;JPO; DERWENT) Text search history attached	7/18/2007	SH
Reviewed correlated application 10/542,017		
Consulted Sue Berman, Primary in class 522	7/10/2007	
Consulted Sean Wu, Primary in class 252	7/10/2007	
STN structure search by STIC, database ref. 229989	7/10/2007	
Interference search cont'd: 349/96,98,113,115,118,176,194	7/18/2007	